

# Webinar powered by First Solar

25 May 2020

4 PM – 5 PM | CEST, Berlin  
10 AM – 11 AM | EDT, New York  
7.30 PM – 8.30 PM | IST, India



**Mark Hutchins**  
Editor | pv magazine



## Quantify the impacts of cell cracking in the field



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## HOW PVEL IS ADDRESSING CELL CRACKING: IN THE LAB AND IN THE FIELD

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# PVEL is the Independent Lab for the Downstream Solar Market

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**Our mission is to support the worldwide PV buyer community by generating data that accelerates adoption of solar technology.**

## **Global**

300+ downstream partners worldwide with 30+GW of annual buying power

## **Comprehensive**

Testing for every aspect of a PV project from procurement to O&M

## **Experienced**

Pioneered bankability testing for PV products nearly a decade ago

## **Market-driven**

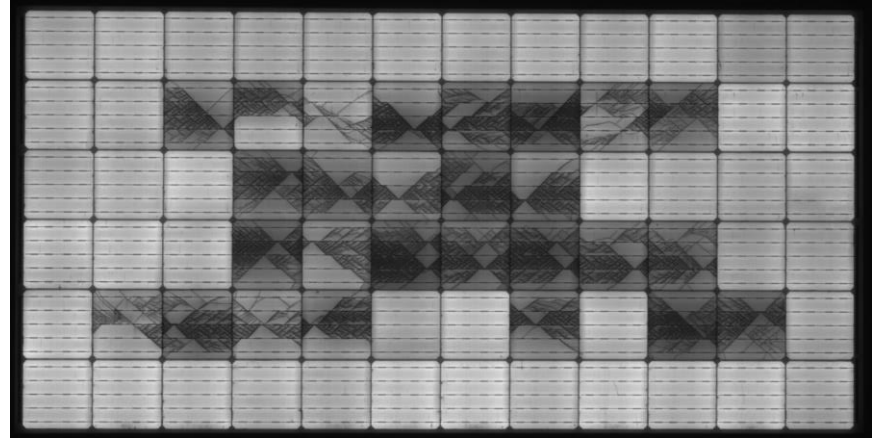
Continuously refining test programs to meet partner needs



# Understanding cell cracking in PV modules

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- › Cells are *quite* thin (<0.2 mm)
- › Glass thickness is 3.2 mm
- › Causes of cell cracks:
  - Manufacturing defects
  - Transportation and shipping
  - improper installation
  - Force majeure/extreme weather events



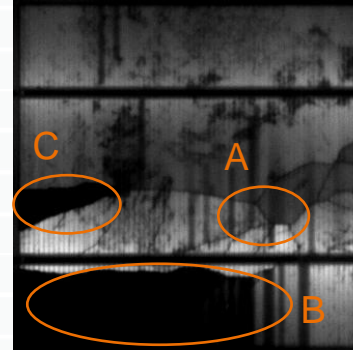
The Main Challenge:  
Power loss is realized **over time** – not right away

## Evaluating power loss and financial loss due to cell cracks

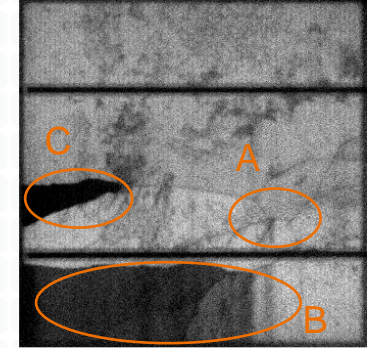
*The bottom line: impact varies*

- › The potential for power loss varies by the type of crack
- › Financial losses depend on model assumptions

EL Image at Isc



EL Image at 1/10 Isc



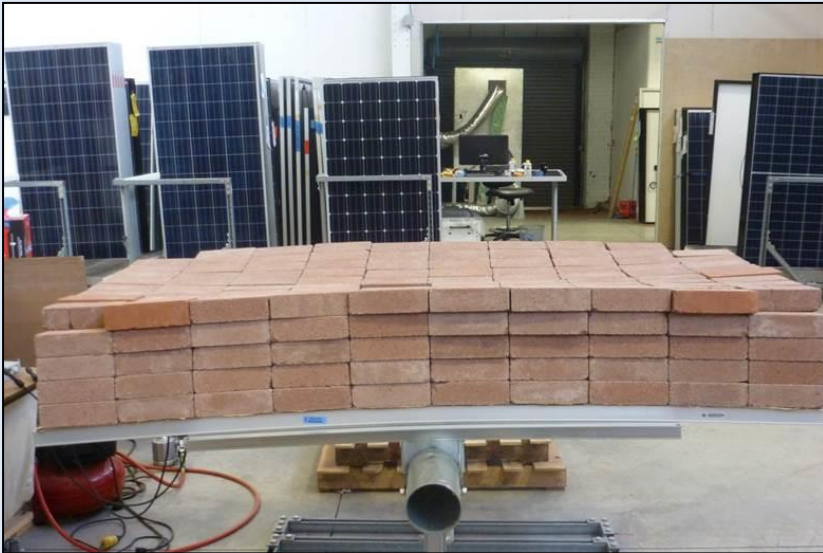
A: No resistance across crack

B: Degraded, still connected, but increased resistance

C: Isolated, inactive cell area

Source: Köntges et al., "Crack statistic of crystalline silicon photovoltaic modules," Institute for Solar Energy Research Hamelin, (2010)

## Certification testing for cell cracks



### > IEC 61215

- Static mechanical load testing at 2400 Pa with options for up to 5400 Pa
- Includes minimum hail testing: 1" hail balls at 50 mph

### > Challenges

- No thermal cycling after stress
- No dynamic mechanical loading
- A pass means:
  - <5% power loss
  - No physical damage
  - **EL imaging not required**

# PVEL's Module Product Qualification Program (PQP) Test Sequences

Factory Witness, Characterizations and Light-Induced Degradation Measurement							
Thermal Cycling	Damp Heat	Backsheet Durability Sequence	Mechanical Stress Sequence	Potential-Induced Degradation	LeTID Sensitivity	PAN File & IAM Profile	Field Exposure
TC 200	DH 1000	DH 1000	Static Mechanical Load	85°C, 85%RH MSV (+ and/or -) 96 hrs	LeTID 162 hrs (75°C, Isc-Imp)	PAN File	Field Exposure 6 Months
Characterization	Characterization	Characterization	Characterization	Characterization	Characterization	IAM Profile	Characterization
TC 200	DH 1000	UV 65 kWh/m²	Dynamic Mechanical Load	85°C, 85%RH MSV (+ and/or -) 96 hrs	LeTID 162 hrs (75°C, Isc-Imp)		Field Exposure 6 Months
Characterization	Characterization	Characterization	Characterization	Characterization	Characterization		Characterization
TC 200	Stabilization 85°C, Isc, 48 hrs	TC 50 + HF 10	TC 50	Characterization	LeTID 162 hrs (75°C, Isc-Imp)		
Characterization	Characterization	Characterization	Characterization	Characterization	Characterization		
		UV 65 kWh/m²	Characterization				
		Characterization	HF 10				
		TC 50 + HF 10	Characterization				
		Characterization					
		UV 65 kWh/m²					
		Characterization					
		TC 50 + HF 10					
		UV 6.5 kWh/m²					
		Characterization					

# PVEL's mechanical stress sequence for cell cracking



Step 1:  
Creates cell cracks in  
susceptible modules

Step 2:  
Articulate cracks,  
opening them in  
susceptible modules

Step 3:  
Reduces power output in  
susceptible modules

*Module types at PVEL queued for MSS testing: monofacial, bifacial, n-type, p-type, 5bb, 6bb, 9bb, 12bb, IBC, MWT, thin film, full cell, half-cut, shingled, 156.75 mm, 158.75 mm, 161 mm, 166 mm, glass//backsheet, glass//glass*



# Improving Cell Cracking Resistance

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## Lower Crack Risk

- › Glass/glass – no tensile stress
- › More interconnect wires – smaller disconnected areas
- › Conductive adhesive (some shingled) – fewer microcracks
- › Parallel wiring – cells less likely to enter reverse bias
- › Better packaging
- › More EL quality control testing – factory, pre and post install
- › Thin film – inherently impervious to cell cracks

## Higher Crack Risk

- › Laser cut cells (half-cut, shingled) – microcracks
- › Larger modules – more deflection and tensile stress
- › Thinner wafers – easier crack propagation

(thanks to Brightspot Automation for this list!)

New Incident Response testing combines advanced field and aerial inspection to safeguard against financial losses

*Field testing:*



*PVEL's aerial inspection partner:*

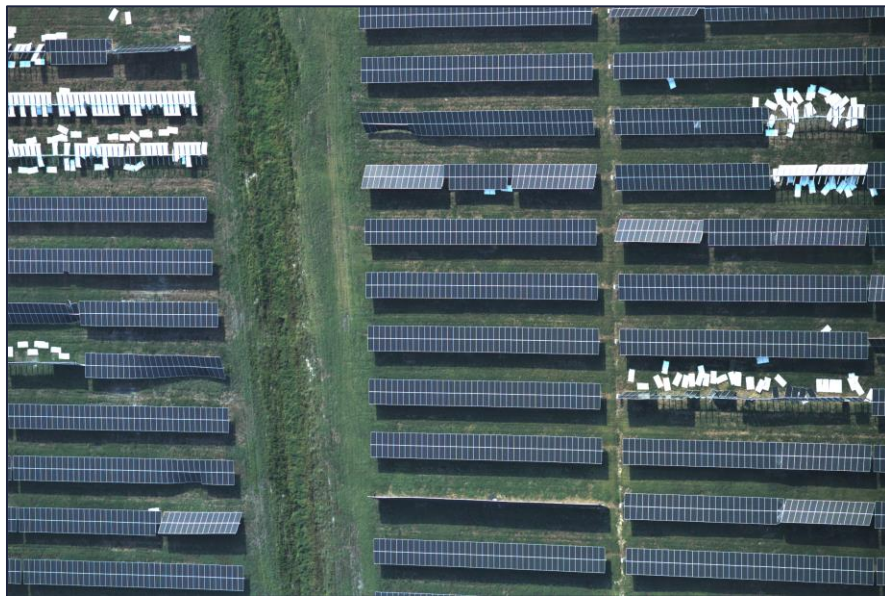


## Hypothetical: A 100 MW site is hit by major wind and hail storm

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- › 270,000 370W modules on site are visually inspected
- › 5% show visible damage and must be replaced – 13,500 modules
- › Assumptions:
  - \$0.25 USD/watt for PV modules
  - \$50/module for labor

**Value of insurance claim for visually  
inspected PV modules:  
\$1.92M**



*100 MW site damaged by  
major wind and hail storm*

*(Image Source: Heliolytics)*

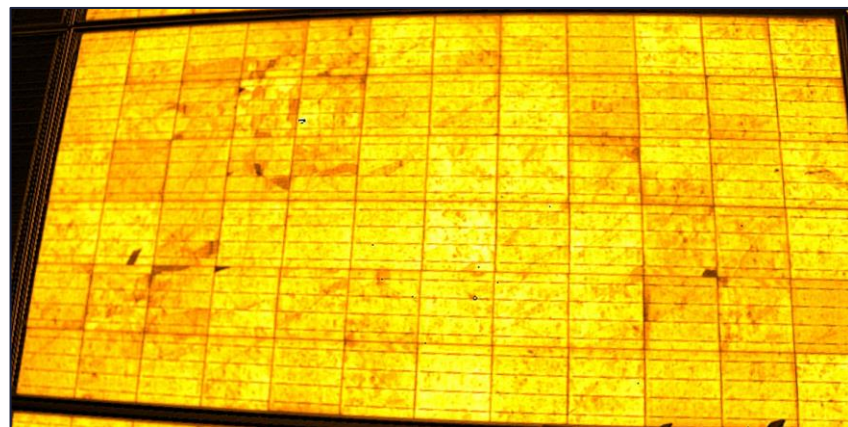


# Insurance payout based on Incident Response

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- › EL imaging reveals that 15% of the modules on site have significant cell cracks
- › An additional 40,500 modules must be replaced

**Total payout for all damaged PV modules:  
\$6.35M – over 3x**



*EL image of cell cracked PV module in the field*





**QUESTIONS, AND THANKS!**

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Out This Week!  
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SIXTH EDITION

## 2020 PV Module Reliability Scorecard



In partnership with

